

1/19

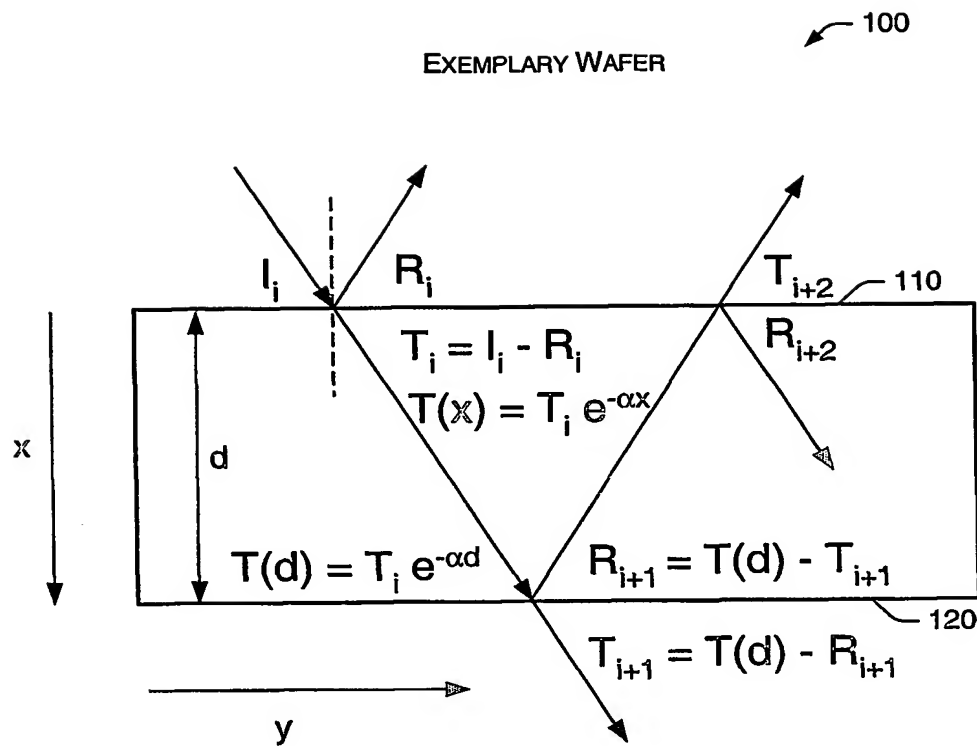


Fig. 1

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EXEMPLARY DEVICE

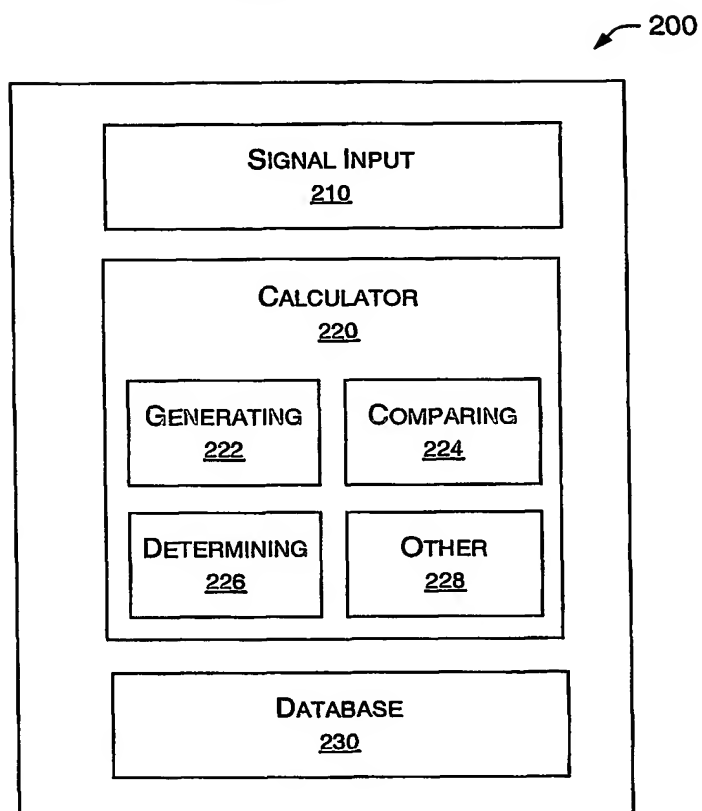


Fig. 2

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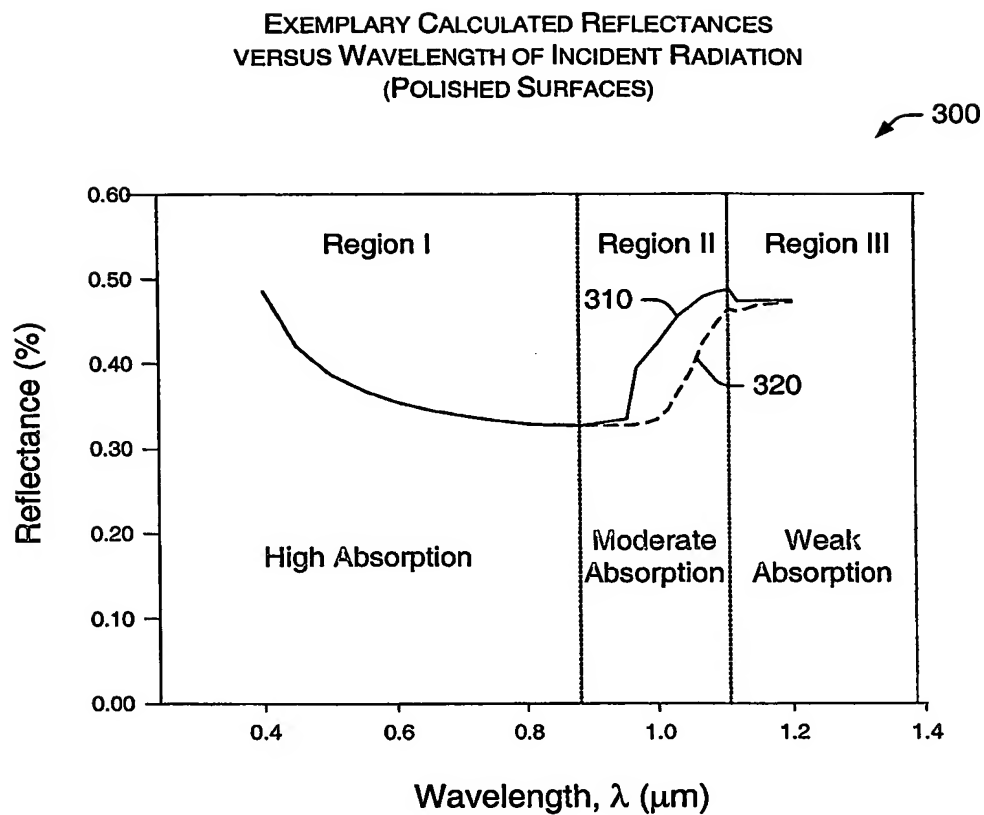


Fig. 3

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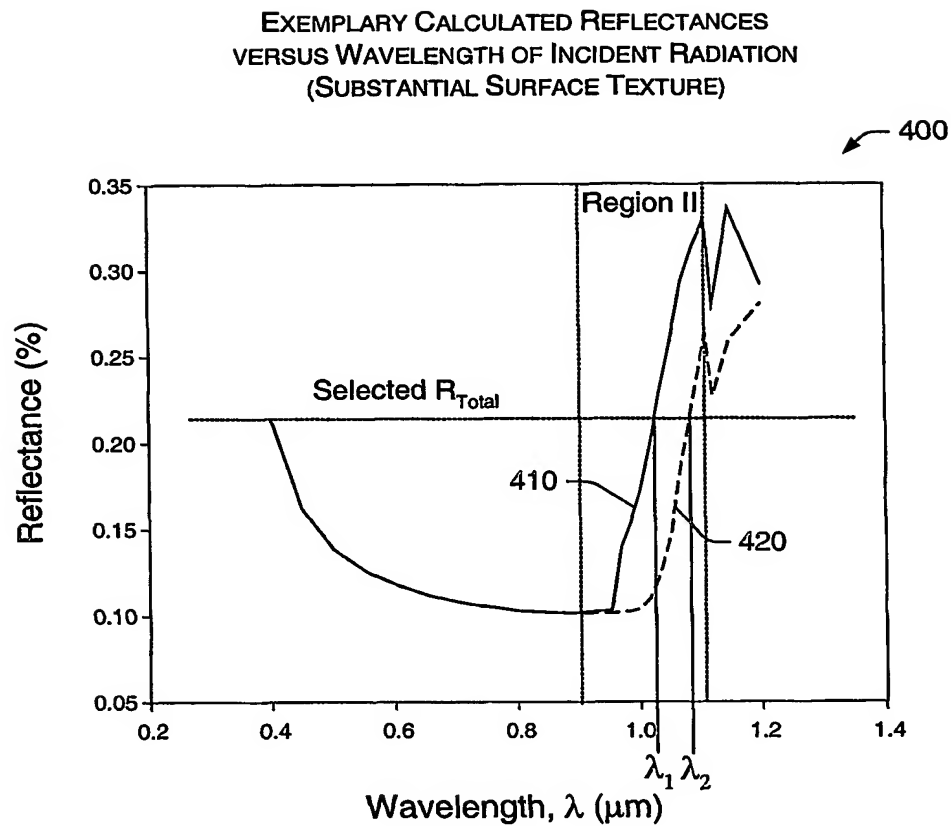


Fig. 4

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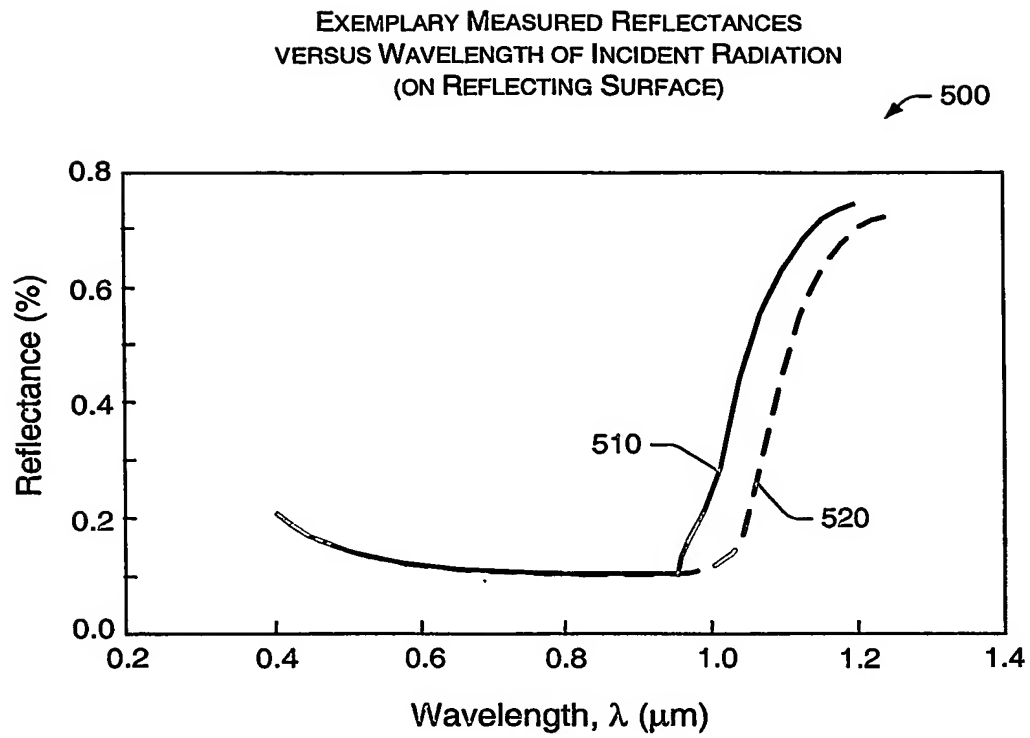


Fig. 5

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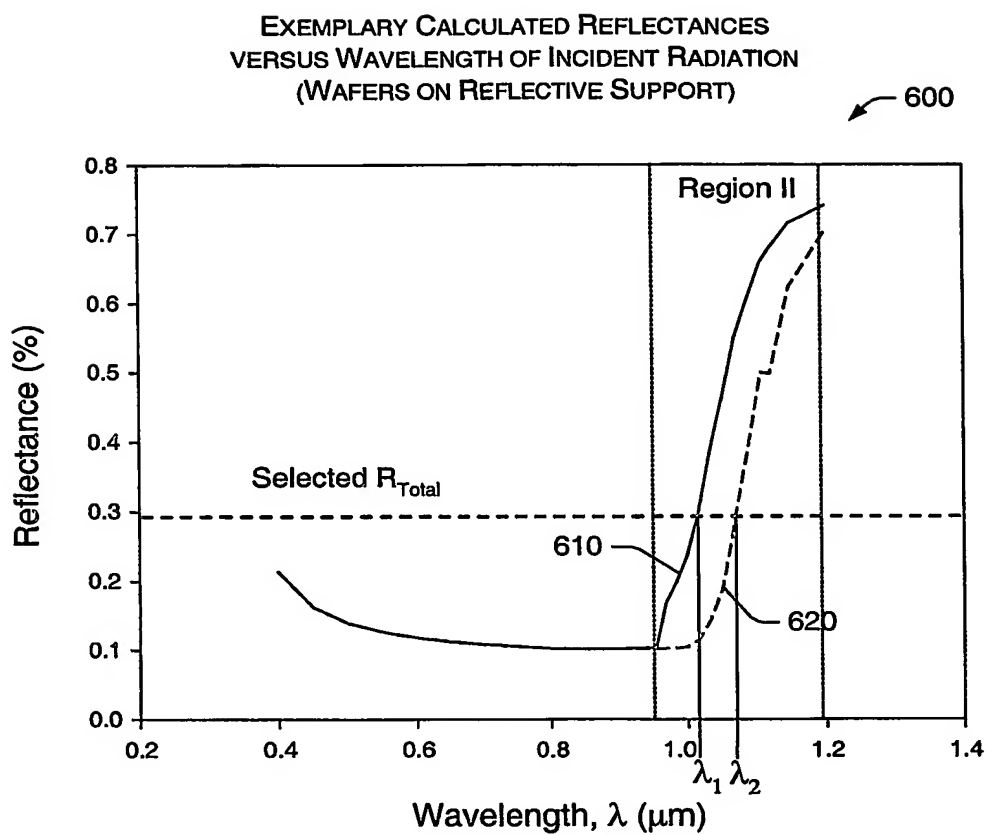


Fig. 6

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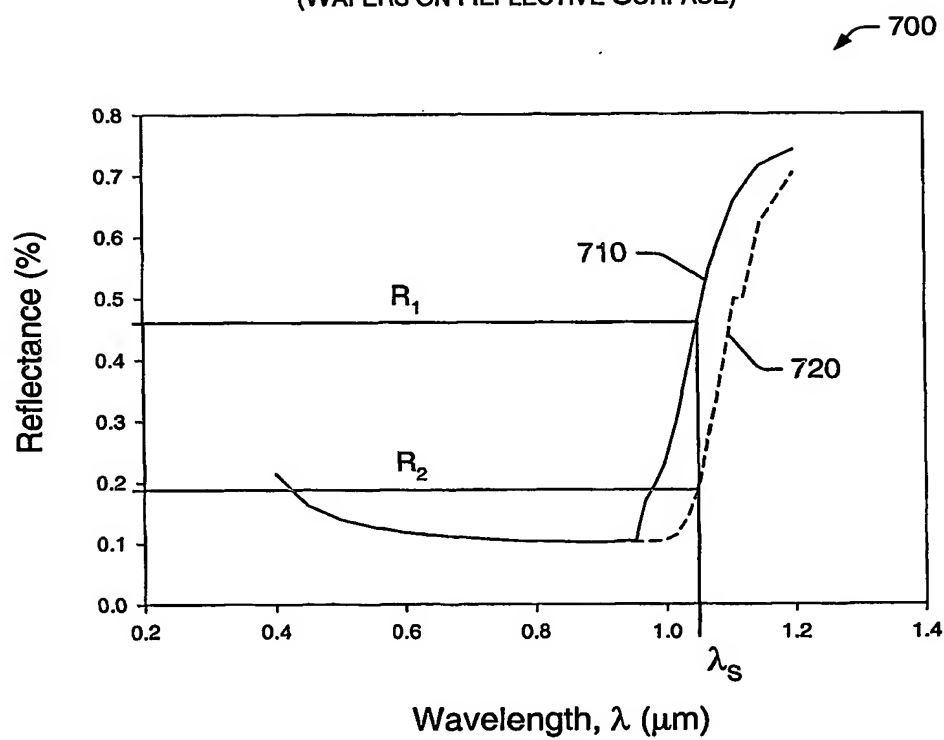
EXEMPLARY CALCULATED REFLECTANCES
VERSUS WAVELENGTH OF INCIDENT RADIATION
(WAFERS ON REFLECTIVE SURFACE)

Fig. 7

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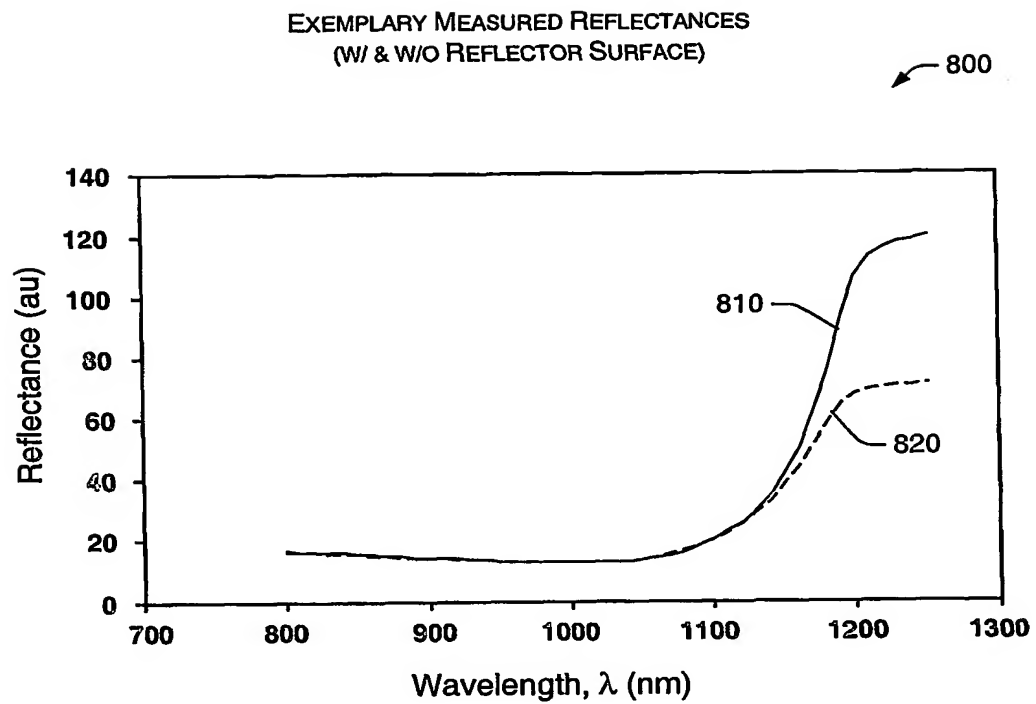


Fig. 8

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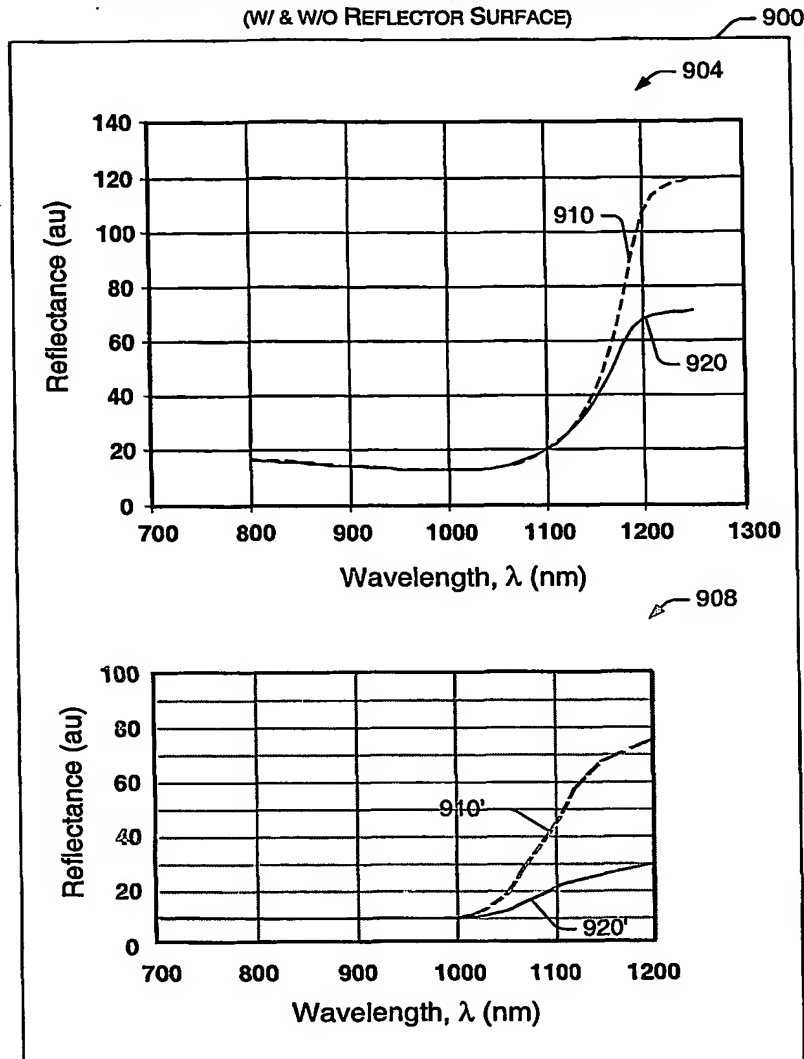
EXEMPLARY COMPARISON OF MEASURED AND CALCULATED
(W/ & W/O REFLECTOR SURFACE)

Fig. 9

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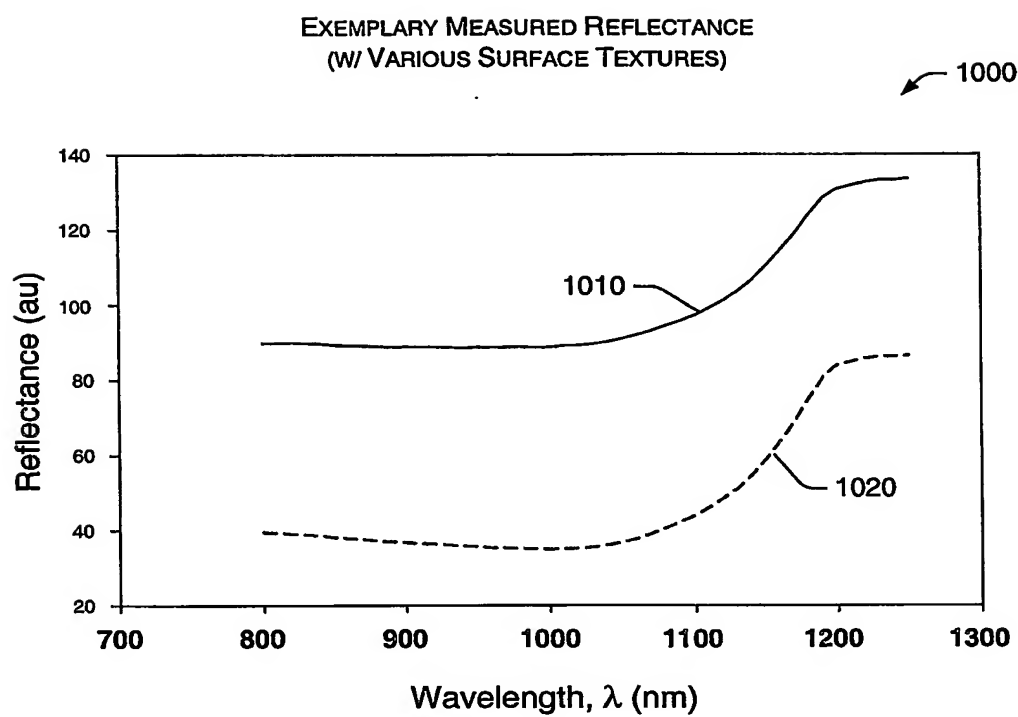


Fig. 10

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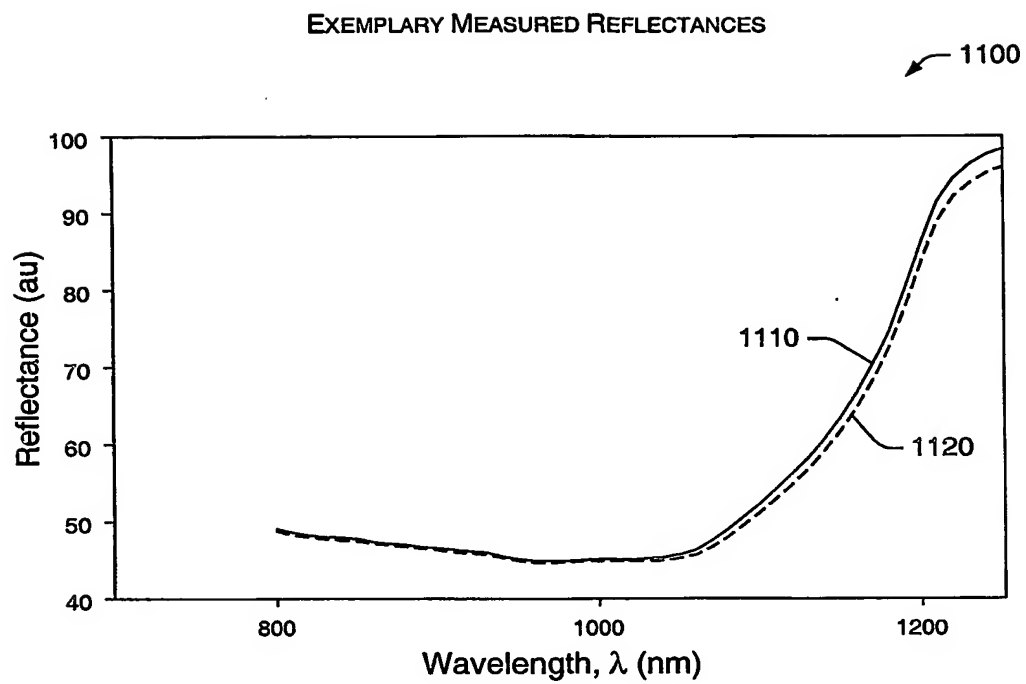


Fig. 11

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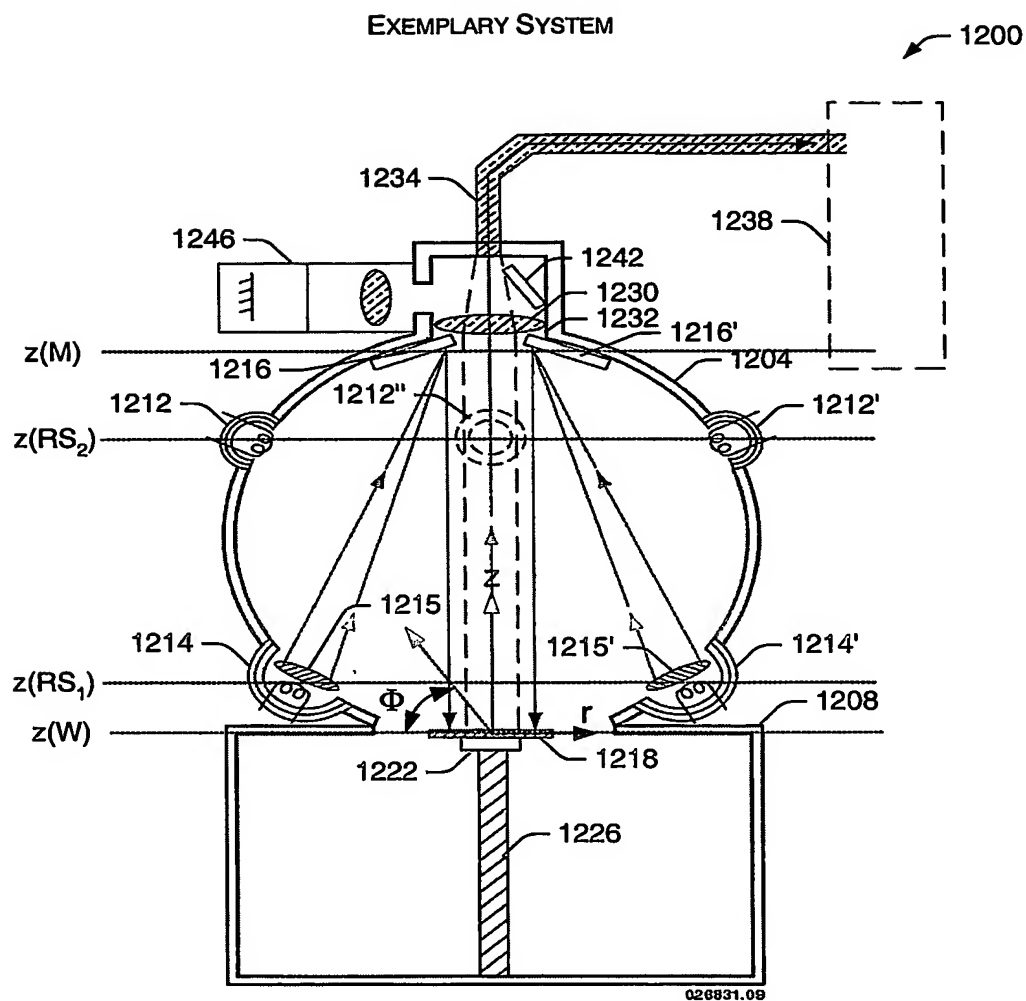


Fig. 12

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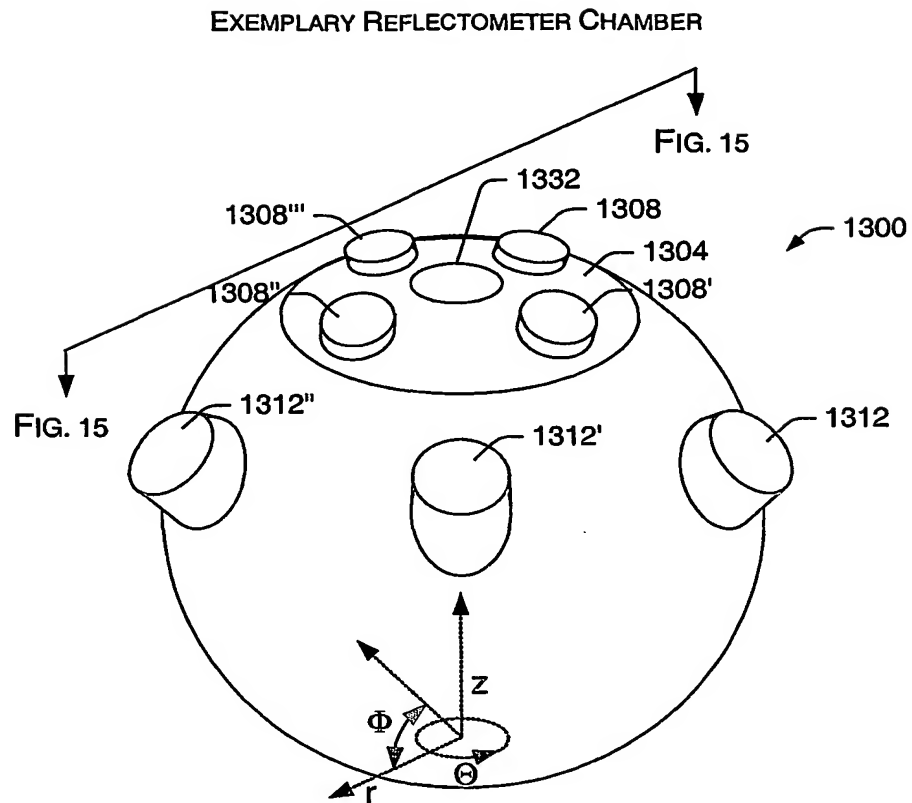


Fig. 13

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EXEMPLARY REFLECTOMETER CHAMBER

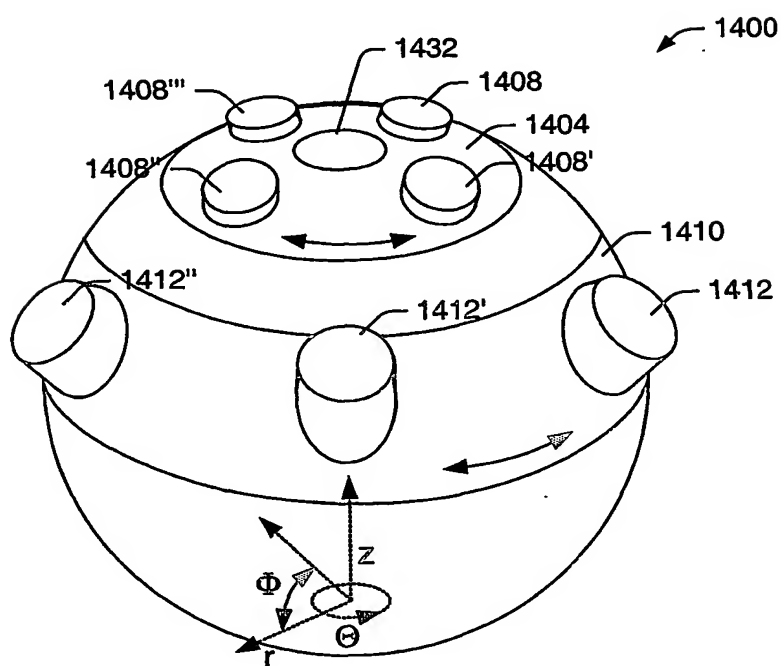


Fig. 14

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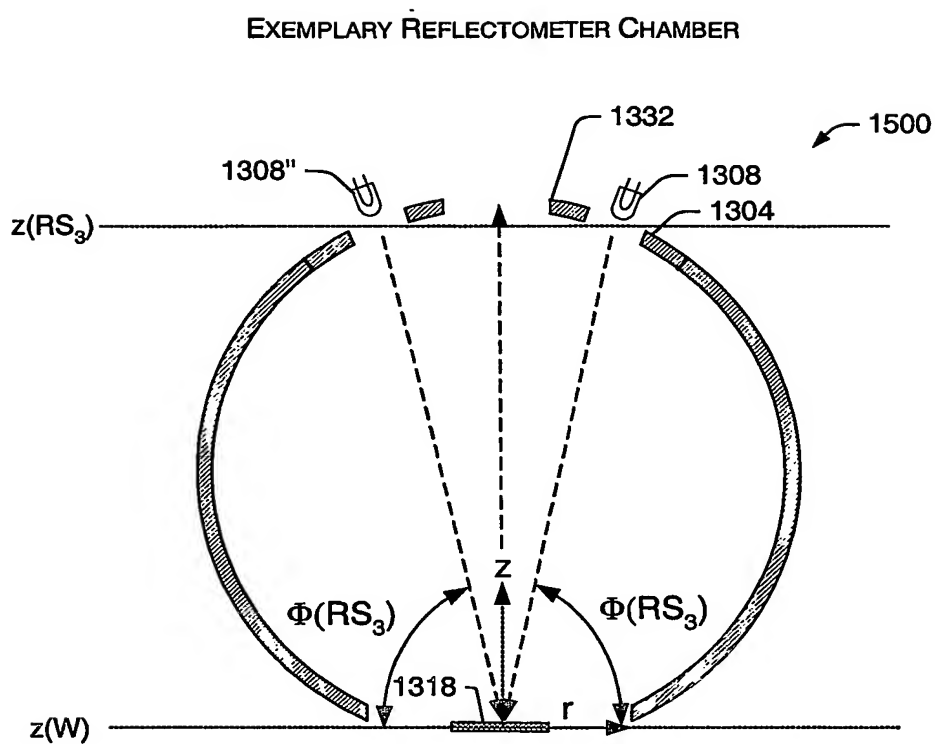


Fig. 15

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EXEMPLARY ELEMENT

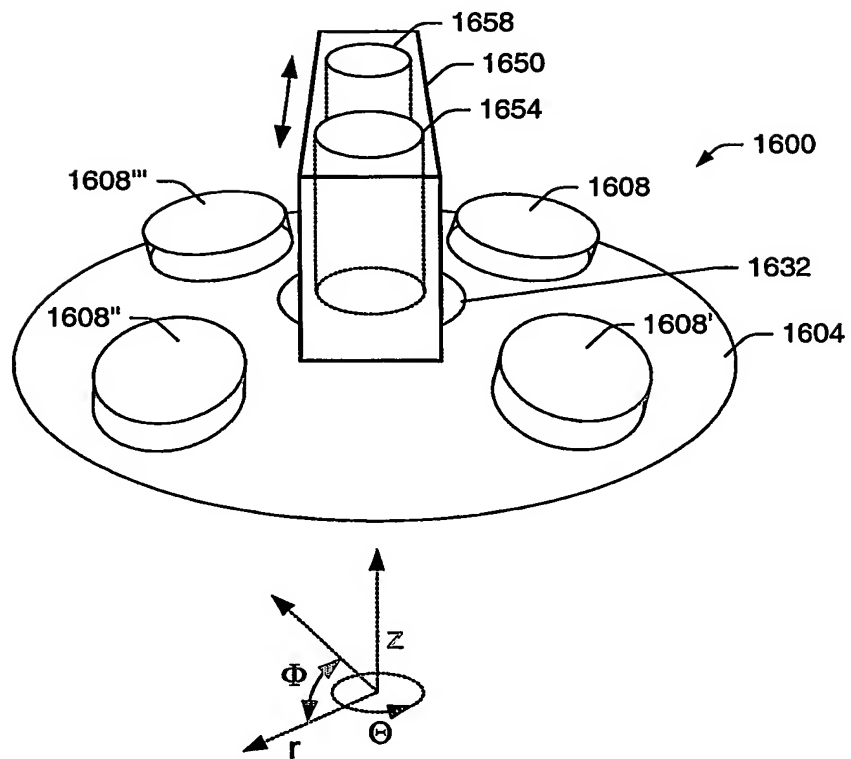


Fig. 16

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EXEMPLARY ELEMENT

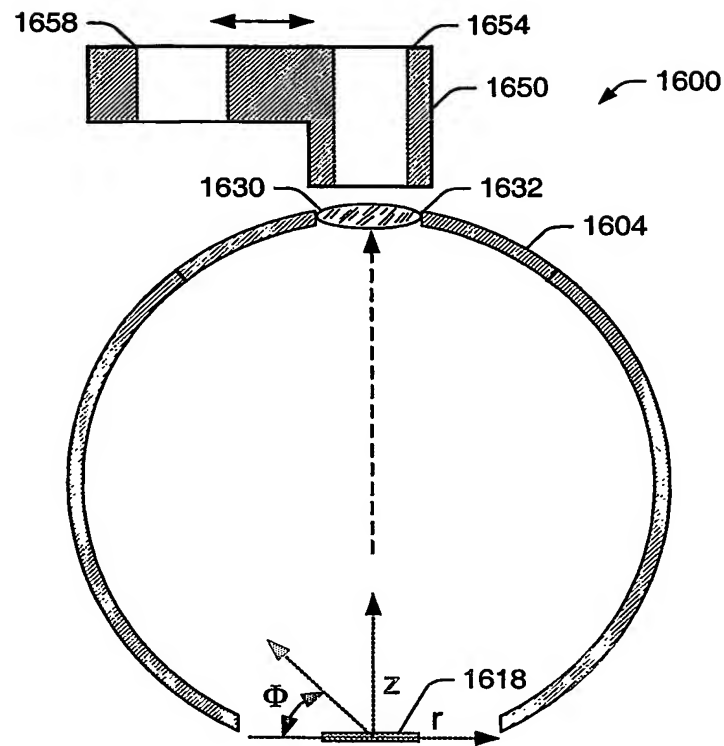


Fig. 17

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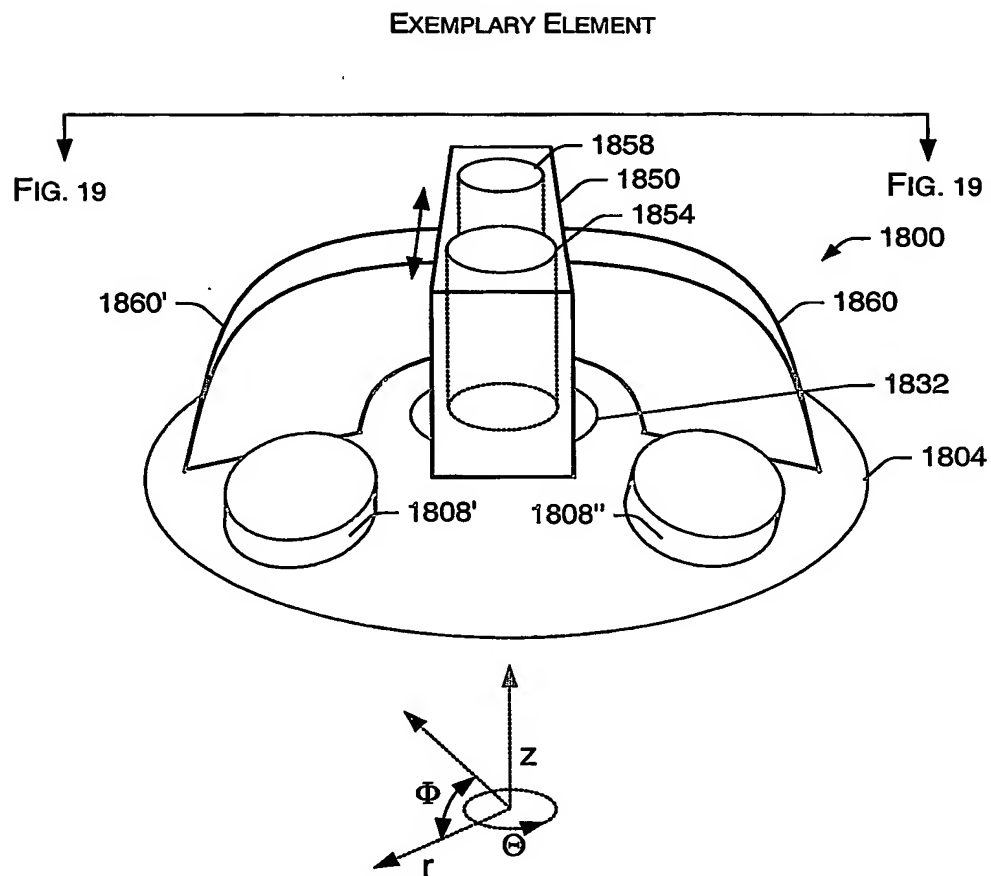


Fig. 18

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EXEMPLARY SYSTEM

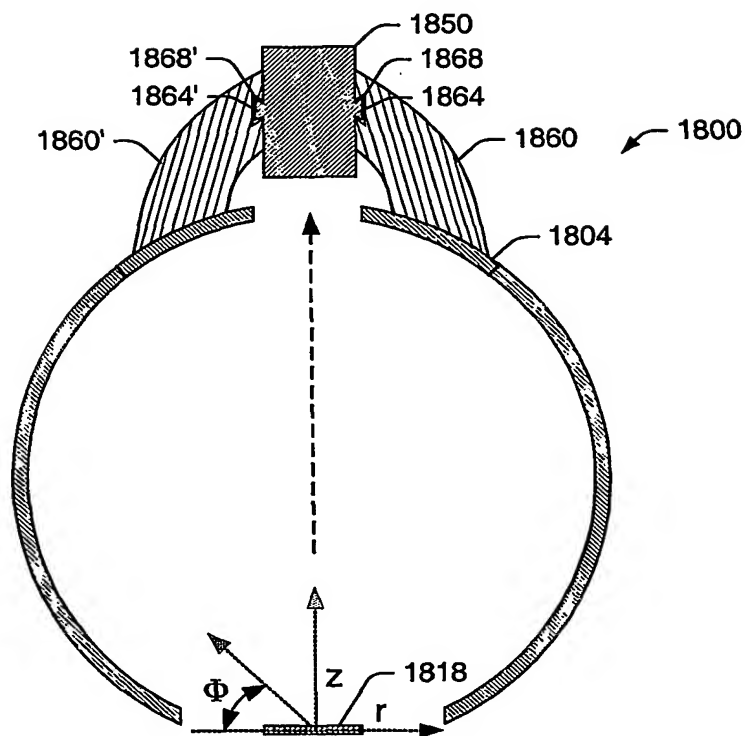


Fig. 19